

Advanced Nanopatterning With Cell Projection Electron Beam Lithography

J. Whittey, M. Haedrich, and I Stolberg

Vistec Electron Beam GmbH, Ilmstr. 4, 07743 Jena, Germany

Electron beam lithography (EBL) can accomplish highly advanced and versatile nanopatterning, due to fine resolution and maskless writing, and is therefore a powerful and widely used method. While mass production in the latest technology nodes is served by specialized and expensive multibeam EBL systems, there is a growing need in other markets for flexible and cost-efficient electron beam writing.

Vistec offers EBL systems which are optimized for fast writing on different types of wafer and mask substrates and have a fully automated substrate handling. These systems are used for fabrication of optical masks in mid-range technology nodes, manufacturing of nanoimprint templates, fast prototyping for initial device evaluation, and manifold small-volume production in semiconductor and micro-optics markets.

Vistec EBL systems utilize electron optics with variable shaped beam, increasing throughput by high-speed variation of the beam size according to the pattern data. With the additional cell projection mode, the electron beam can be pre-shaped to multiple profiles (cells), e.g. dot arrays or line gratings or circle elements, and many others. Thousands of different customized cells can be implemented in a single EBL system. Thereby not only repetitive structures are exposed even faster, with simultaneously smoother pattern edge. Due to the ability to perform dense patterning on large areas in a feasible time, ambitious applications become possible, like metasurfaces with high optical quality on full 300 mm wafers.

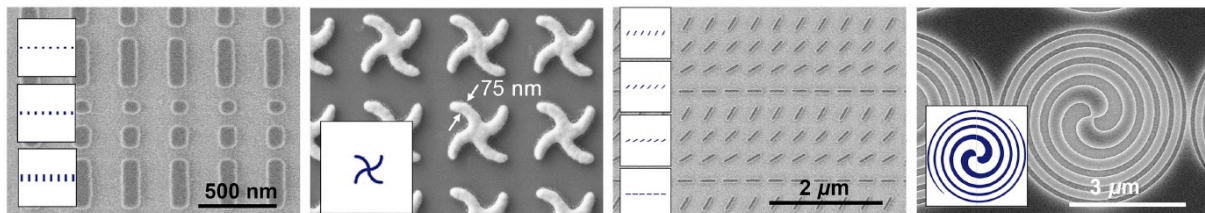


Fig. 1: SEM-images of complex patterns generated by EBL with the cell projection. The insets are showing the pre-shaped beam profile. From: U.D. Zeitner, M. Banasch, M. Trost, J. Micro/Nanopattern. Mater. Metrol. 22(4) 041405-3 (2023).

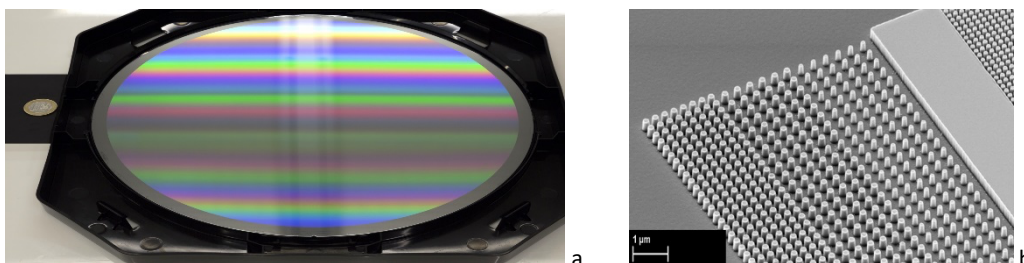


Fig. 2: a) 300 mm wafer fully patterned with an effective-medium blazed grating by cell projection. b) SEM image of the grating dots. From: M. Haedrich, et al., PhotonicsViews 5/2022, DOI: 10.1002/phvs.202200036.